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Form PTO 1449
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U.S. Department of Commerce
Patent and Trademark Office

App. Docket No.
Mo-6644 LeA-34 976

Serial No.
29 998 560

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Applicant
Kristina Vogt et al.
Filing Date
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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPRO- PRIATE
L.T.M.-E	AA 15870 4915870	04 10 90	Jones	252	313 2	
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FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						Yes	No*
L.T.M.-E	EP 0 634 465 A1	01/18/95	Europe				
	AM						
	AN						
	AO						
	AP						

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

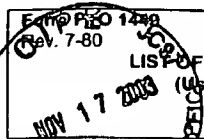
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	U.S. Department of Commerce Patent and Trademark Office		Atty. Docket No. Mo-6644/LeA-34,976	Serial No. 09/998,560
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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5,614,449	03/25/97	Jensen	501	38	
	AB	5,755,946	05/26/98	Ferronato	205	110	
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							Yes	No*
<i>297/E</i>	AL	164439	10/31/75	Hungary				x
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	AP							

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EXAMINER	<i>Lynette J. McEwen</i>	DATE CONSIDERED <i>4/22/2004</i>
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09/998560
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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							Yes	No*
LJME	AL	WO 00/00567	01/06/2000	World Patent	—	—		
LJME	AM	WO 00/24842	05/04/2000	World Patent	—	—		
LJME	AN	WO 99/64527	12/16/99	World Patent	—	—		
LJME	AO	WO 99/47618	09/23/99	World Patent	—	—		
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LJME	AR	Microchip Fabrication: A Practical Guide to Semiconductor Processing, Peter Van Zant ed., McGraw-Hill (month unavailable) 2000, pages 302-309 & 401-403
LJME	AS	Copper CMP: A Quistion of Tradeoffs, Peter Singer, Semiconductor International, Verlag Cahnner, May 2000, pages 73-84
LJME	AT	Chemical Mechanical Planarization of Microelectronic Material, J.M. Steigerwald, S.P. Murarka & R.J. Gutmann, John Wiley & Sons, Inc. (month unavailable) 1997, CMP Variable and Manipulations, pages 42-43

EXAMINER	Lynette T. Olney-Eumini	DATE CONSIDERED	4/22/2004
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